

DUT1505 – 500V, 15A

August 2009 **Preliminary** *Mintech*

HIGH EFFICIENCY, TEMPERATURE INDEPENDENT GaAs RECTIFIER DIODE

General Description

The DUT1505 is a GaAs P-I-N Rectifier. It uses a patented liquid phase epitaxy (LPE) construction to provide temperature performance above current Silicon, Silicon Carbide and Gallium Nitride products of a similar specification. The device is able to function stably well above the maximum T_J of more traditional diodes of this type while maintaining parity of performance in terms of key parameters such as recovery time and forward voltage.

Package Types



TO-276AB

1

3

COMMON CATHODE

COMMON CATHODE

ANODE

2

1

2.

TO-257

TO-276AB (SMD) BARE DIE

0

Features

High maximum junction temperature; up to

Lower and temperature independent

dynamic recovery characteristics over the

+260 ℃ vs. +175 ℃ for silicon diodes

Lower leakage current at all operating

full specified temperature range

High temperature electronics

Power Modules

Applications

temperatures

Very low capacitance

Hybrid circuits

Thermal Characteristics

SYMBOL	PARAMETER	PACKAGE	RATINGS	UNITS
R _{θJC}	MAXIMUM THERMAL RESISTANCE, JUNCTION TO CASE	TO-276AI	3.51	°C/W
R _{ejc}	MAXIMUM THERMAL RESISTANCE, JUNCTION TO CASE	TO-257AIN	1.45	°C/W
R _{eJC}	MAXIMUM THERMAL RESISTANCE, JUNCTION TO CASE	TO-276AB	1.24	°C/W

TO-257AI / TO-257AIN



BARE DIE (3.1mm²)



2. ANODE (DIE BACKSIDE)

ORDERING PART #	PACKAGE	TEMP RANGE	
DUT1505AL	TO-257AI	-65 TO 260℃	
DUT1505ALN	TO-257AIN	-65 TO 260 ℃	
DUT1505S	TO-276AB	-65 TO 260 ℃	
DUT1505-AG	BARE DIE	-65 TO 260 ℃	
DUT1505-GG	BARE DIE	-65 TO 260℃	
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Absolute Maximum Ratings

SYMBOL	PARAMETER	RATINGS	UNITS
V _{RRM}	PEAK REPETETIVE REVERSE VOLTAGE	500	V
V _{RWM}	WORKING PEAK REPETETIVE REVERSE VOLTAGE	500	V
V _R	DC BLOCKING VOLTAGE	500	V
I _{F(AV)}	AVERAGE RECTIFIED FORWARD CURRENT @ 260 ℃	15	A
I _{FSM}	NON-REPETETIVE PEAK SURGE CURRENT 60Hz SINGLE HALF-SINE WAVE	150	A
T _J ,T _{STG}	OPERATING AND STORAGE TEMPERATURE RANGE	-65 to +260	Ç

Electrical Characteristics

SYMBOL	PARAMETER		MIN	ТҮР	МАХ	UNITS
V _{FM} 1	I _F =15A	T _c = 25 ℃ T _c = 175 ℃ T _c = 260 ℃		1.8 2.1 2.3	1.9 2.2 2.5	V
I _{RM} 1	V _R =500V	T _C = 25 ℃ T _C = 175 ℃ T _C = 260 ℃		0.40 125 1000	1 130 1100	μΑ
t _{RR}	I _F =1A, di/dt = 200 A/μs, V _R =30V	T _c = 25 ℃ T _c = 175 ℃ T _c = 260 ℃		30 30 30	35 35 35	ns
t _{rr} I _{rr} Q _{rr}	I _F =15A, di/dt = 200 A/μs, V _R =200V	T _C = 25 ℃	- -	65 9 300	75 10 370	ns A nC
t _{RR} I _{RR} Q _{RR}	I _F =15A, di/dt = 200 A/μA, V _R =200V	T _c = 175℃	- - -	65 9 300	75 10 370	ns A nC
t _{RR} I _{RR} Q _{RR}	I _F =15A, di/dt = 200 A/μA, V _R =200V	T _C = 260 ℃	- - -	65 9 300	75 10 370	ns A nC
CJ	T _J = 25 ℃, f = 1MHz, V _R = 200V	-	-	18	22	pF
W _{AVL}	AVALANCHE ENERGY(L=2Mh)	-	10	-	-	mJ

Notes: 1: Pulse: Test Pulse width = 300µs, Duty Cycle = 2%

Typical Performance Characteristics















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